

Laser diode quantum efficiency revisited

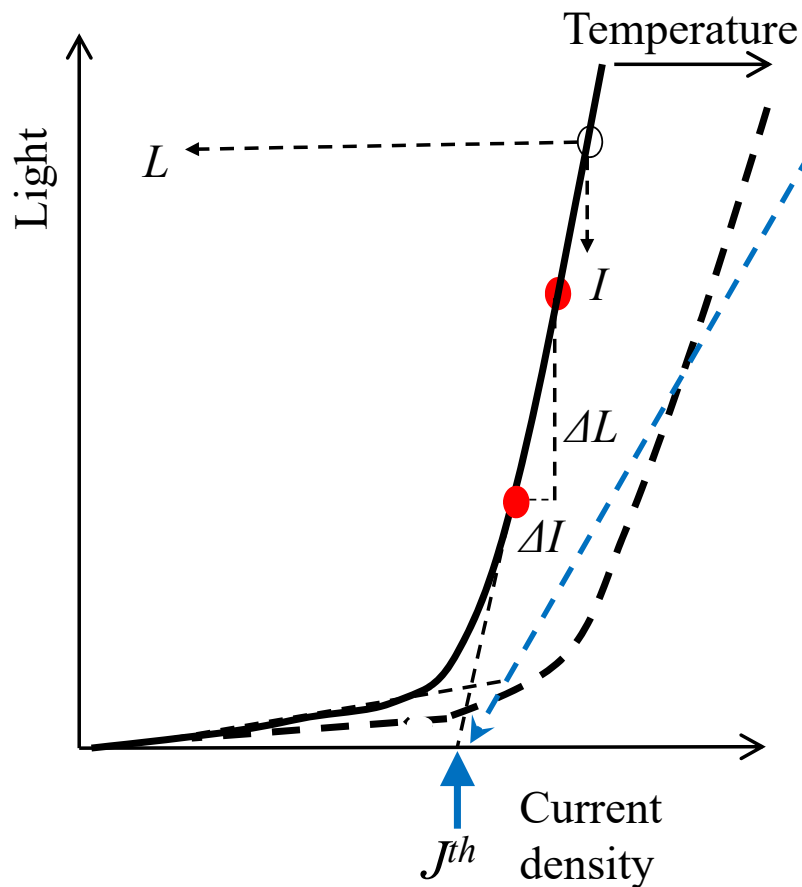
from the worries of a beginner in 1983
to a contemporary problem

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Measured light-current characteristic



The **external current at threshold** J_{ext}^{th} :

- non-radiative recombination in the gain medium
- current lost by leakage and spreading
- intrinsic radiative (spontaneous) current, J_{spon}^{th} , which drives gain generation and can be calculated.

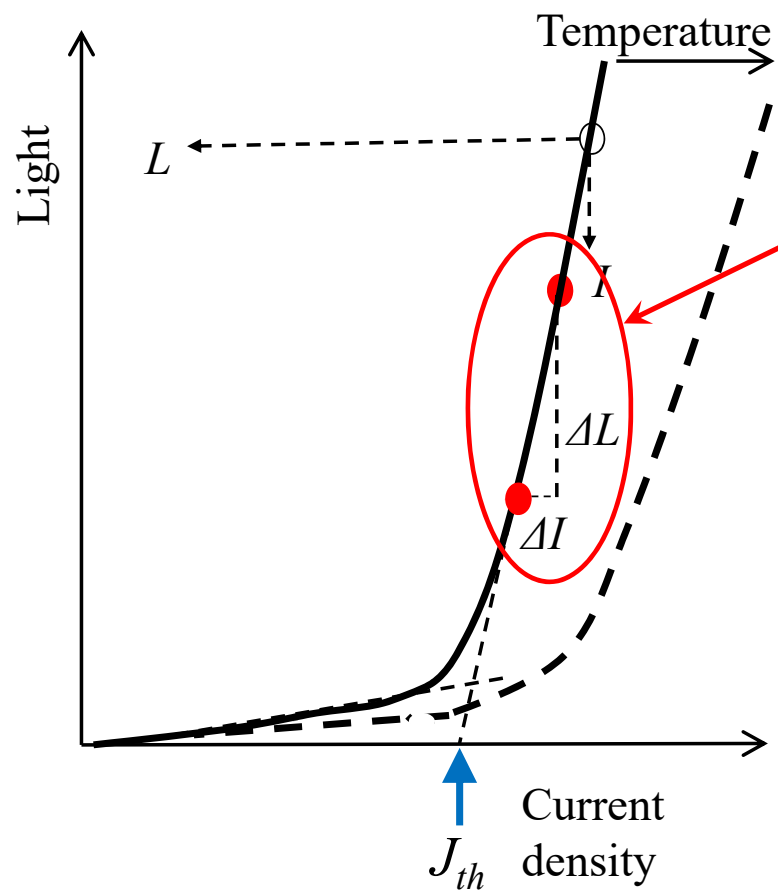
$$J_{spon}^{th} = \eta_0 J_{ext}^{th}$$

Efficiency η_0 is not known:

sample and structure dependent

- How can measurement and theory for threshold be compared?

Measured light-current characteristic



Above threshold:

External **differential** quantum efficiency in the lasing mode:

$$\eta_{ext}^d = \frac{\text{external photon emission rate increment}}{\text{external current increment}/e}$$

$$\frac{1}{\eta_{ext}^d} = \left\{ 1 + \frac{\alpha_i}{\ln(R^{-1})} L_c \right\} \frac{1}{\eta_0^d}$$

(Baird, Carr and Reed, 1964)

$1/\eta_{ext}^d$ versus cavity length L_c has intercept $1/\eta_0^d$

Measurements

Typical experimental values give η_0^d 0.6 to 0.9.

η_0^d regarded as the “internal quantum efficiency”.
Used to obtain spontaneous current at threshold
to compare with theory.

Problem solved?

Two worries:

1. Why is η_0^d from the intercept < 1 ?
Fermi level pinning above threshold
stimulated emission efficiency is 1.
2. Can we obtain *overall* efficiency at
threshold from a *differential* efficiency
above threshold?

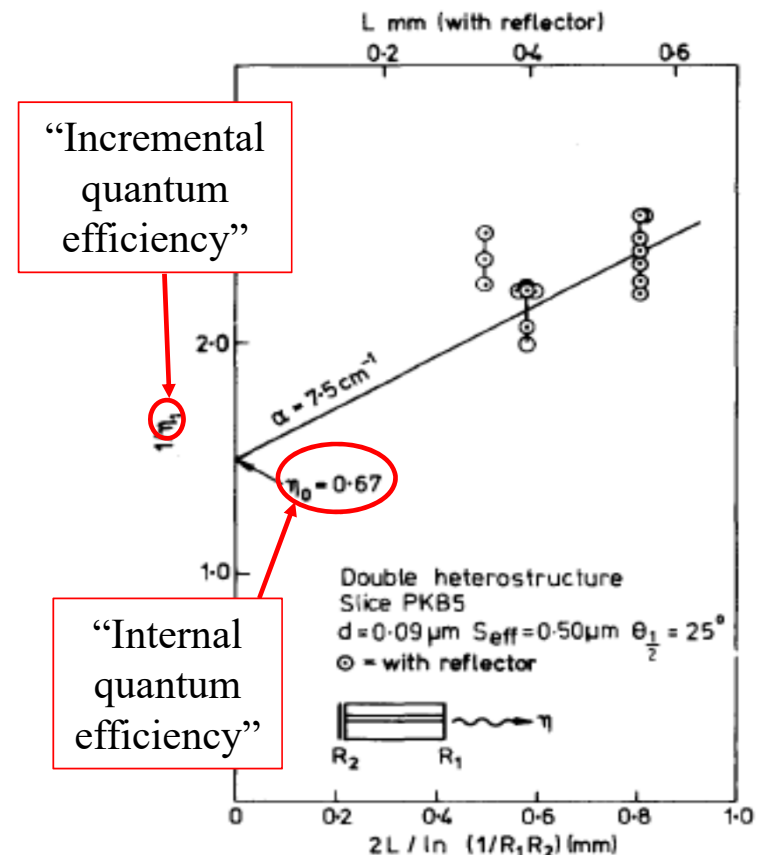


FIG. 11. Incremental quantum efficiency versus laser length for narrow-beam DH lasers.

Thompson et al 1976

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DATE 13 June 1994.

studying Casey and Panish

Notation not consistent

Some notes from Thompson's book

b96.

Equation (286) for
cent above threshold :

I wonder whether our values of τ_i are being modified by current spreading into regions where the gain is not saturated.

→ Could be tested by looking for ~~thin~~ spon emission, and by measuring the optical distⁿ.
This effect will mean that η_0 above threshold could be significantly less than 100%, and in good mtrl could be less than η_{spon} just below thr.

...on the next page...answer to Q1

Calculated stimulated current versus external current for stripe laser by Hakki (1975)

Differential injection efficiency about 0.8 due to increasing current spreading above threshold.

64

DATE 12 July 1999

Hakki (TAP 46, 292 (1975)) has done calculations of the current distribution in stripe geometry lasers, and has calculated the stimulated current as a function of the contact current (see opposite) and concludes that even if the internal stimulated recombination process is 100% efficient, the observed efficiency will be 32% and ~ 80% for 10 μm and 20 μm wide stripes resp, just based on the relation between J_{stim} and J_c .

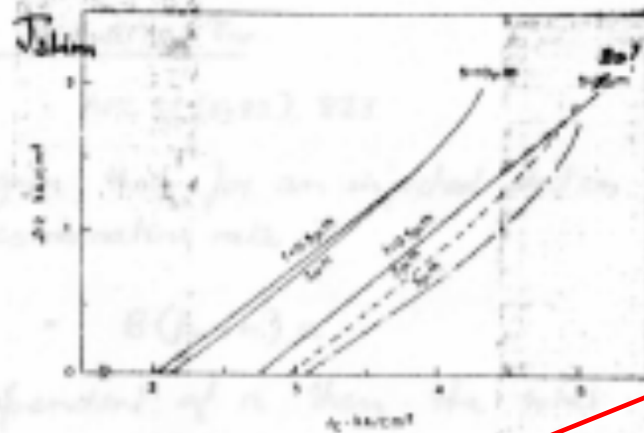
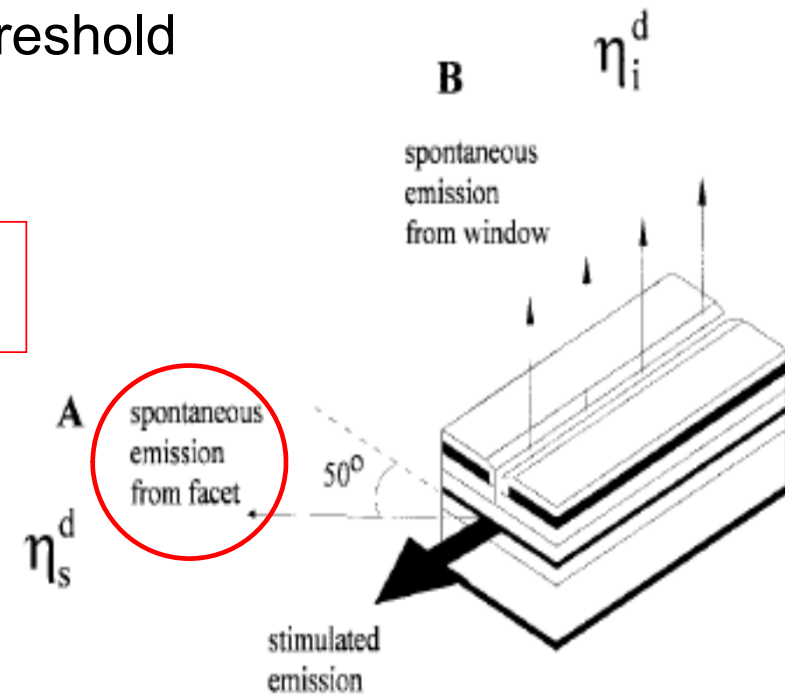
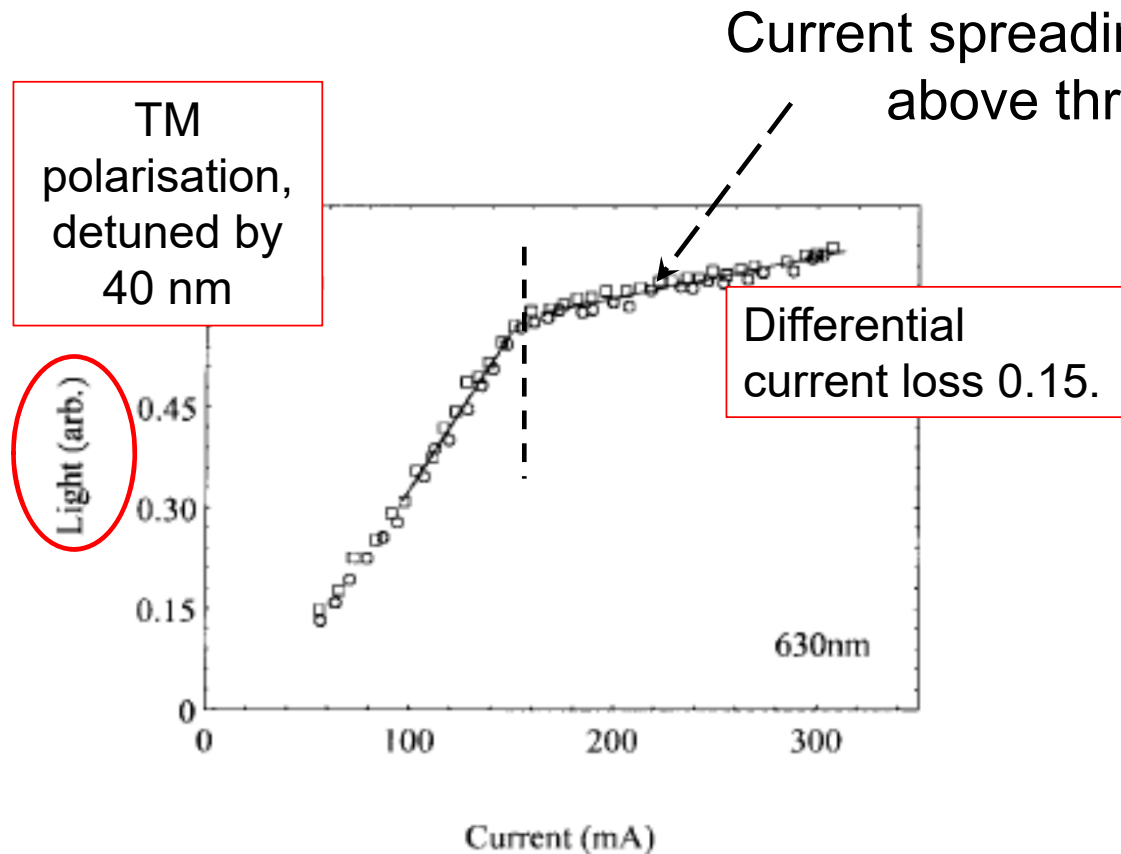


FIG. 8. Stimulated junction current dependence on contact current for a stripe geometry GaAs DB junction laser for stripe widths of 10 and 20 μm , respectively, and different thicknesses of the resistive layer.

B.M. HAKKI 259

Experiments, 10 years later!



Smowton and Blood, JSTQE 3 (1997) 491

Current paths

Above Threshold:

- External differential efficiency:
externally measured light and current

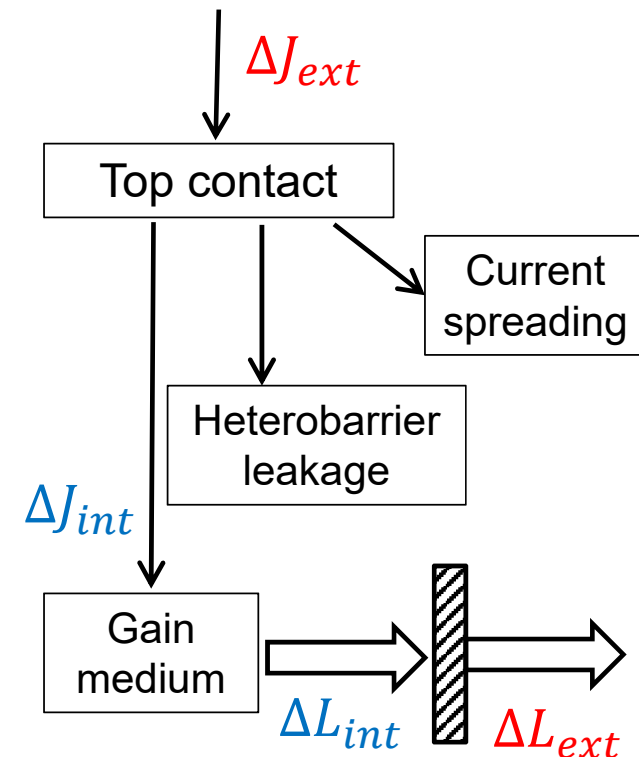
$$\eta_{ext}^d = \frac{e\Delta L_{ext}}{\Delta J_{ext}}$$

- Internal differential efficiency:
Ratio of increments in rate of injection of electron-hole pairs (current) into gain region to the photon emission rate from this region.

$$\eta_{int}^d = \frac{e\Delta L_{int}}{\Delta J_{int}}$$

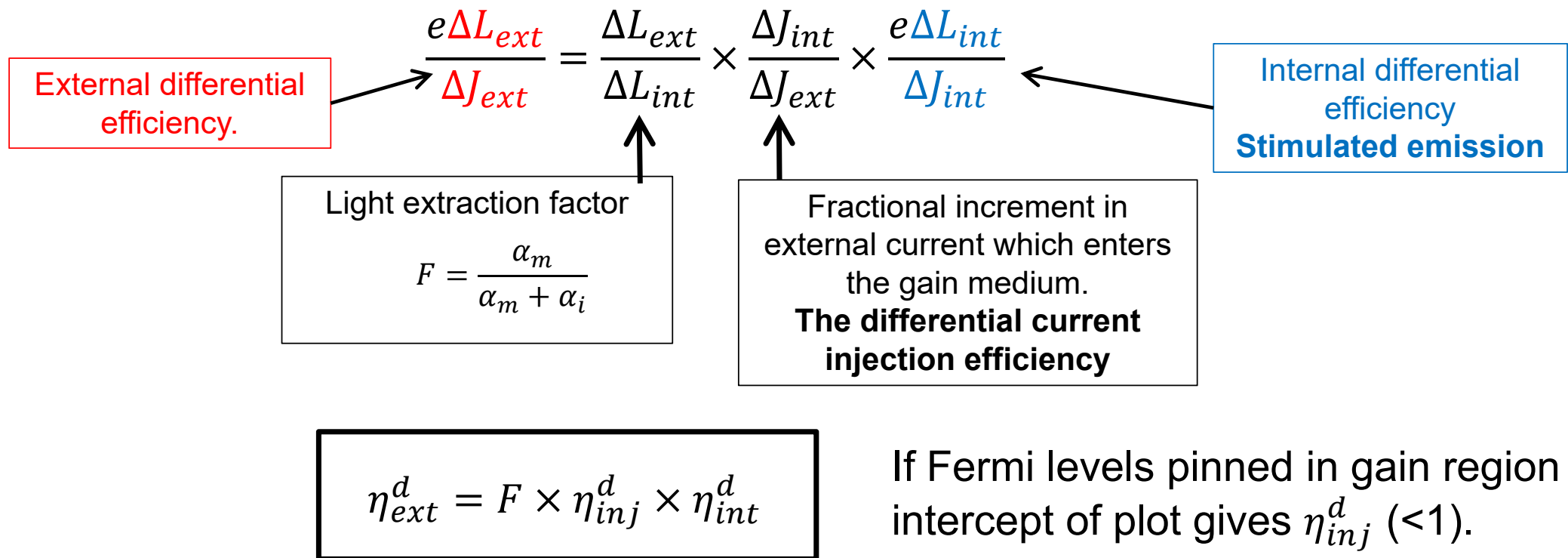
If Fermi levels pinned $\eta_{int}^d = \eta_{stim} = 1$

Current paths



Differential efficiencies above threshold

Taking account of internal and external light and current:



If Fermi levels pinned in gain region intercept of plot gives η_{inj}^d (<1).

Overall efficiency at threshold

Internal spontaneous radiative efficiency is $\eta_{int}^{spon} = \frac{R_{spon}}{R_{spon} + R_{nr}} = \frac{eR_{spon}}{J_{int}}$

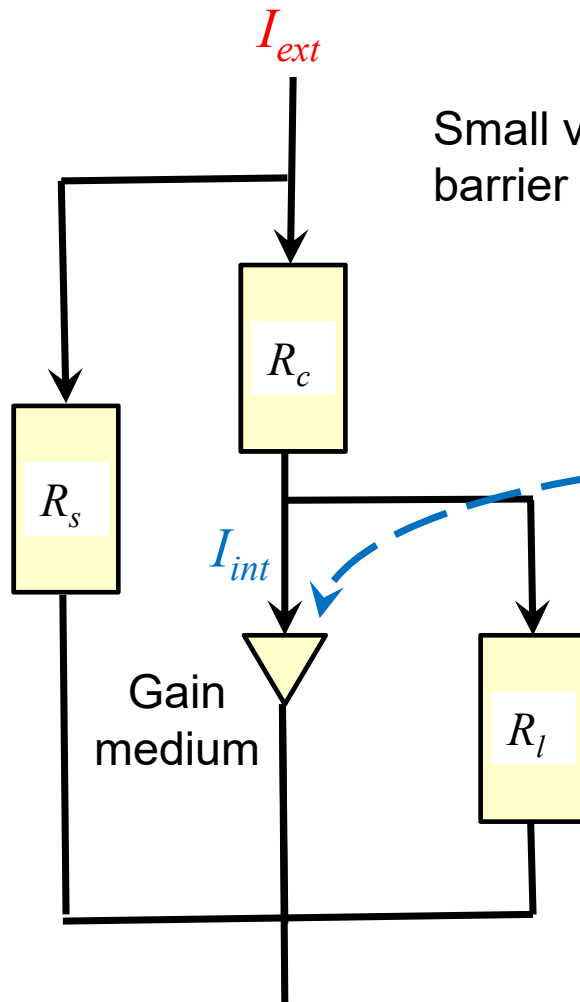
The overall injection efficiency is $\eta_{inj} = \frac{J_{int}}{J_{ext}}$

Spontaneous Emission
in all directions

$$J_{spon}^{th} = \eta_0 J_{ext}^{th} = [\eta_{int}^{spon} \times \eta_{inj}] J_{ext}^{th}$$

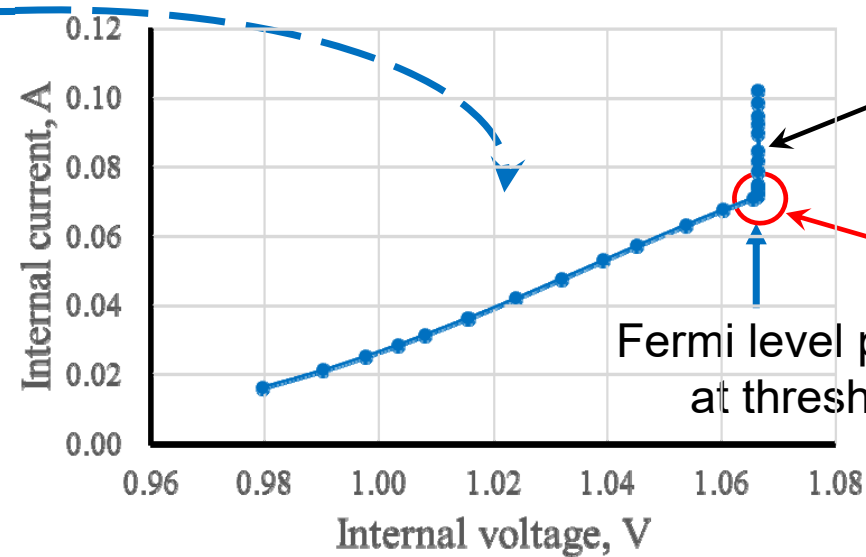
- **Question 2: Does overall injection efficiency at threshold
= differential injection efficiency above threshold ?**

External and internal current



Small voltage range around threshold, represent current spreading, hetero-barrier leakage and series resistance as linear resistive elements.

Internal I-V characteristic of gain medium assuming quasi-thermal equilibrium



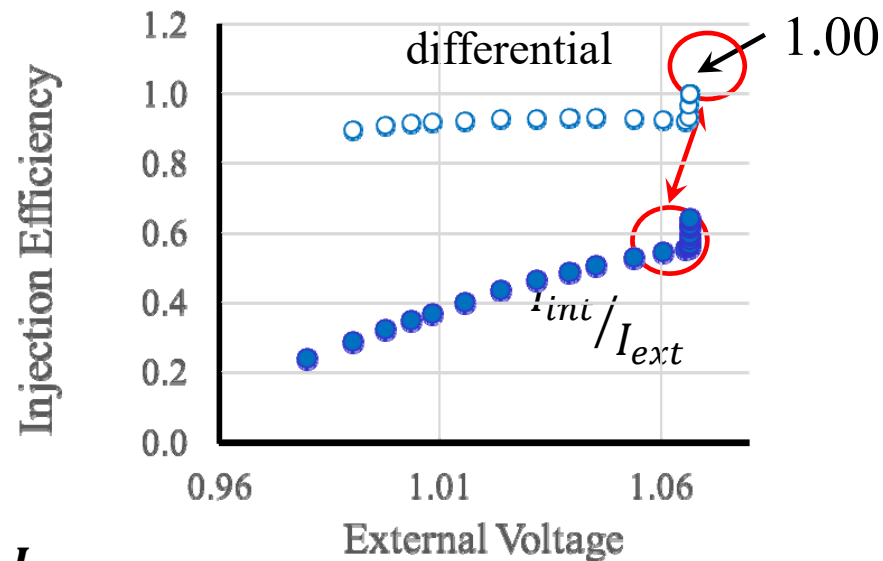
Stimulated emission.
Zero differential resistance above threshold

J_{spon}^{th}

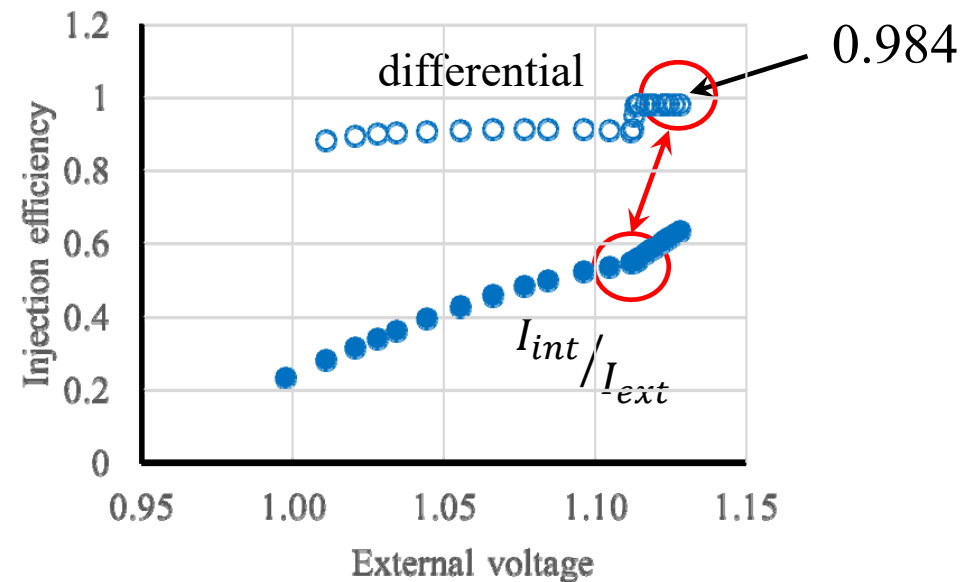
Fermi level pinning at threshold

Injection Efficiency

$R_c = 0$: Fermi level pinning everywhere



$R_c > 0$: Current spreading and external voltage not pinned at threshold



I_{int}/I_{ext} at threshold is not equal to differential injection efficiency above threshold

An example: quantum dot active region

Random population at low temperature, probably thermal at threshold at room temperature, but.....

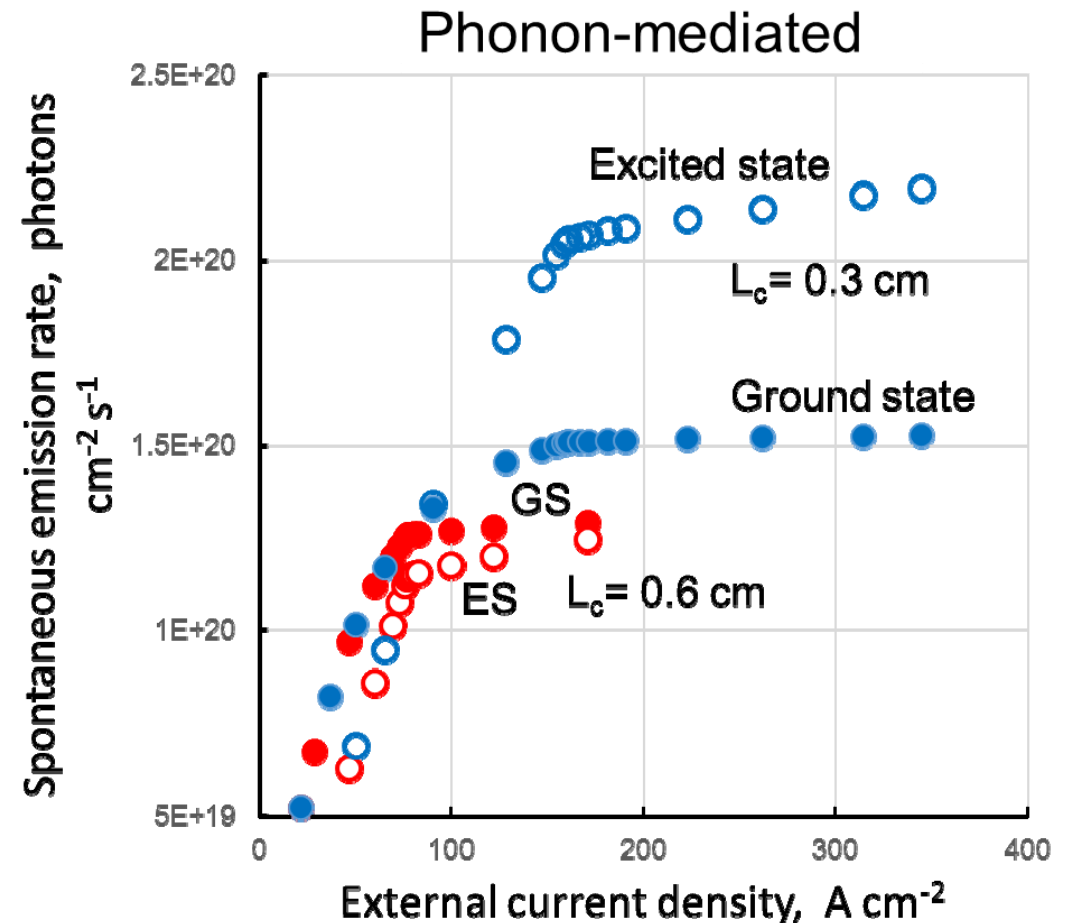
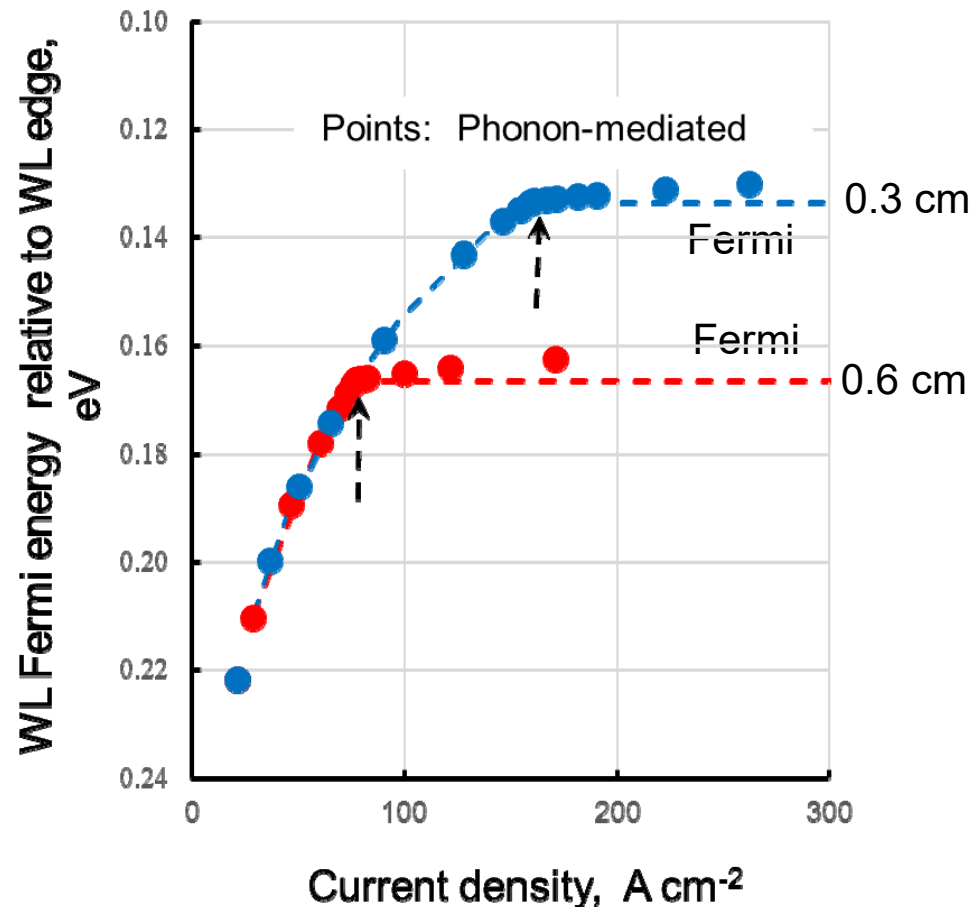
Spontaneous emission dots does not pin above threshold at room temperature. (Smowton, unpublished, Marko et al, IET Opto, vol 8 (2014) 88-93).

Single mode laser rate equation model for

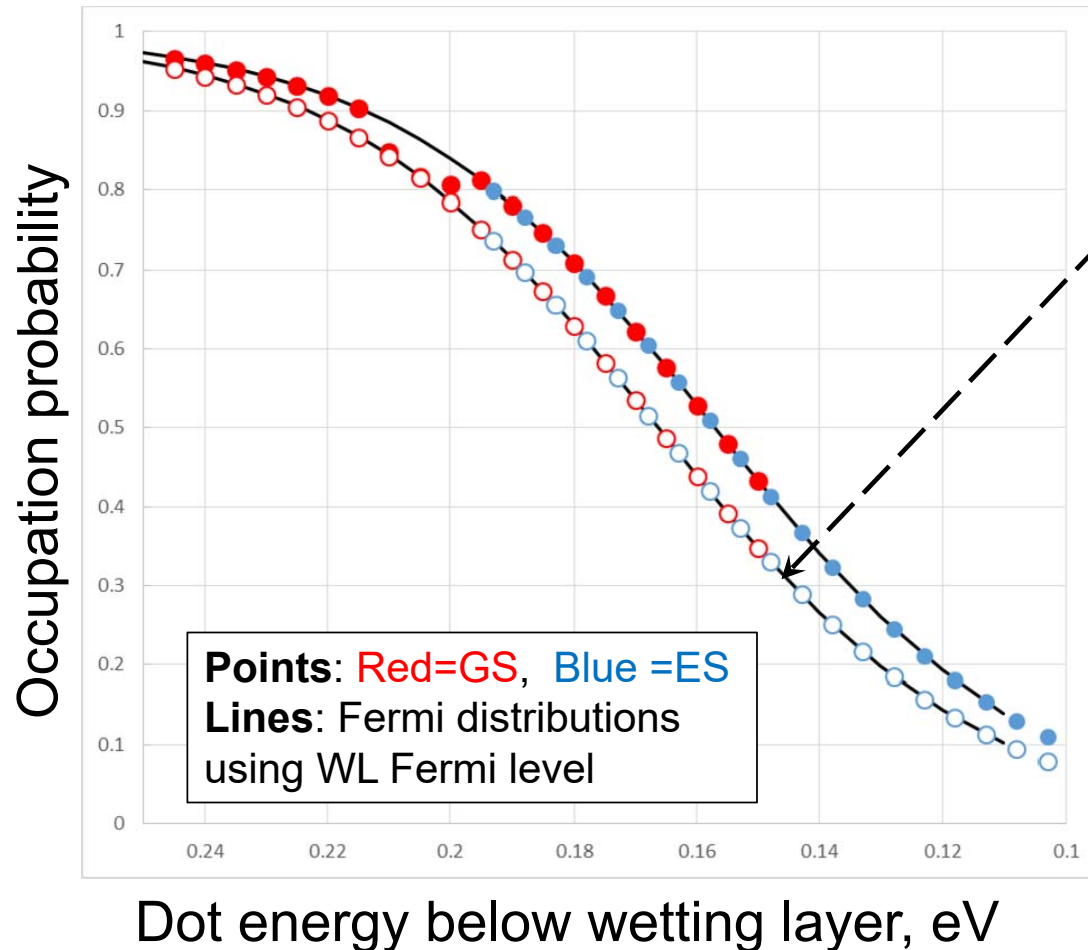
1. dots in thermal equilibrium with the wetting layer using Fermi-Dirac statistics (pinning in dots and WL),
2. dot occupation from interaction with wetting layer (WL) via a Bose-Einstein distribution of phonons without prior assumption of equilibrium. P Blood, Quantum Confined Laser Devices, OUP 2015, p 222; Finch et al J Sel Topics QE vol 21 (2015), 1900507

With heterobarrier leakage and current spreading.

Wetting layer Fermi level, dot spontaneous emission



Dot occupation distributions: Phonon model



WL occupation at threshold is in thermal equilibrium with wetting layer.

WL carrier density and Fermi level not pinned above threshold

Lasing dots:

Gain and occupation pinned by laser action.

Non-lasing dots:

GS and ES in quasi-equilibrium with WL, but occupation not pinned. Spontaneous emission increases.

Effect of stimulated emission

- All dots have the same capture rate from uniform carrier distribution in WL.
- Recombination rate in dot = non-rad + spon + stim.

➤ In **non-lasing dot**, no stim emission

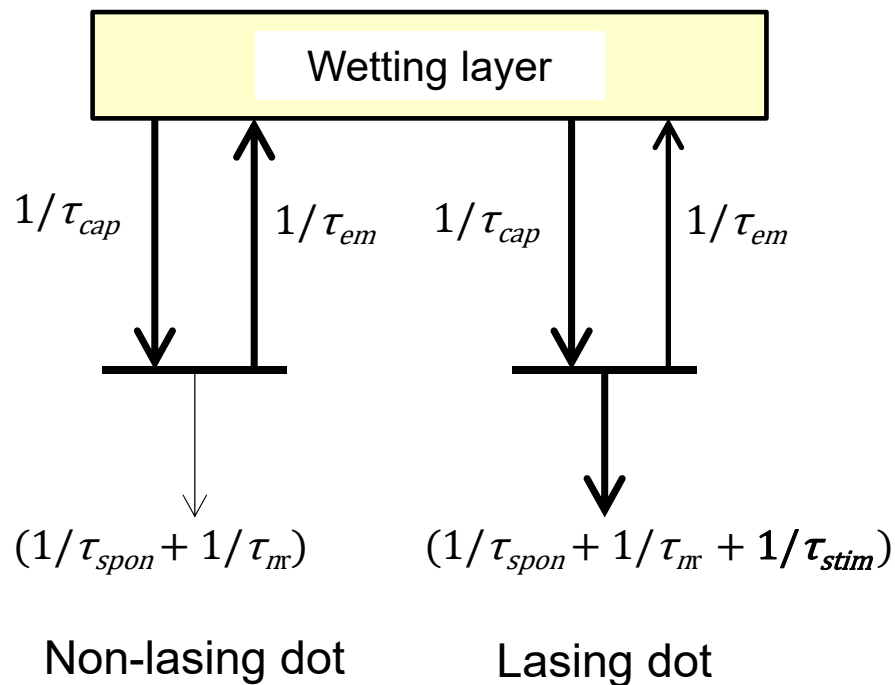
$$\frac{1}{\tau_{em}} \gg \frac{1}{\tau_{spon}} + \frac{1}{\tau_{nr}} \quad f_g = \frac{1}{1 + \frac{\tau_{cap}}{\tau_{em}}}$$

Occupation varies with energy of state: emission rate decreases with increasing energy separation.

➤ In **lasing dot**, strong stim emission

$$\frac{1}{\tau_{em}} \ll \frac{1}{\tau_{stim}} \quad f_g = \frac{1}{1 + \frac{\tau_{cap}}{\tau_{stim}}}$$

Occupation determined by stim rate: photon density.
WL carrier density increases.

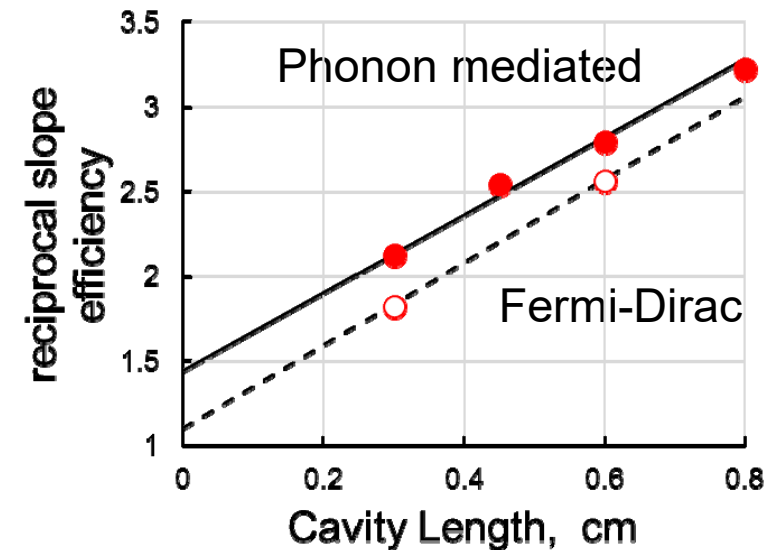


Differential current components above threshold

- Wetting layer carrier density not pinned:
 - Wetting layer recombination
 - Heterobarrier leakage
 - Current spreading
 not pinned.

Differential Injection efficiency
 into dots $\eta_{inj}^d = 0.86$
 (Overall injection efficiency at threshold=0.45)

- Spontaneous emission of dots not pinned:
Differential internal efficiency
 of dot system $\eta_{int}^d = 0.91$



Differential injection efficiencies length dependent.
 Input value $\alpha_i = 3 \text{ cm}^{-1}$
 From plot $\eta_{ext}^d - L_c$ plot $= 1.92 \text{ cm}^{-1}$

Summary

In general $\eta_{ext}^d = F \times \eta_{inj}^d \times \eta_{int}^d$

- If Fermi levels pinned *everywhere* $\eta_{int}^d = 1$, $\eta_{inj}^d = 1$: intercept of plot = 1
- If Fermi levels pinned in gain medium only $\eta_{int}^d = 1$ but $\eta_{inj}^d < 1$

But if η_{inj}^d varies with L_c plot has no meaning.

- Internal radiative efficiency at threshold difficult to measure directly
- Injection efficiency at threshold not equal to
the differential injection efficiency above threshold.
- Quantitative comparison of experiment and theory still difficult.

Don't be afraid to challenge the accepted wisdom if you have good cause.